## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: HAMAMATSU, et al.

Filed: December 2, 2003

METHOD FOR INSPECTING DEFECT AND APPARATUS FOR

**INSPECTING DEFECT** 

## **CLAIM FOR PRIORITY**

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

December 2, 2003

Sir:

For:

Under the provisions of 35 USC §119 AND 37 CFR § 1.55, Applicants hereby claim the right of priority based on Patent Application No. 2002-349357 filed in <u>Japan</u> on <u>December 2, 2002</u>.

Under the provisions of 35 USC §119, Applicants hereby claim the right of priority based on Patent Application No. 2002-347134 filed in Japan on November 29, 2002.

A certified copy of 2002-347134 was filed in parent application U.S. Serial Number \_\_\_\_\_, filed November 28, 2003, by Hamamatsu et al, entitled "Inspection Method and Inspection Apparatus".

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS, LLP

Melvin Kraus

Registration No. 22,466

1300 North Seventeenth Street Suite 1800 Arlington, VA 22209

Tel.: 703-312-6600 Fax: 703-312-6666

MK/alb